

N-channel TrenchMOS intermediate level FET Rev. 1 — 12 July 2011

Product data sheet

1. **Product profile**

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard and logic level gate drive sources

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

Table 1. **Quick reference data**

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; [1] see <u>Figure 1</u>	-	-	90	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see Figure 2	-	-	128	W
Static char	racteristics					
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u>	-	4.4	5.2	mΩ



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Table 1.	Quick reference datacor	nnued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} &I_D = 90 \text{ A}; \text{V}_{\text{sup}} \leq 30 \text{V}; \\ &R_{\text{GS}} = 50 \Omega; \text{V}_{\text{GS}} = 10 \text{V}; \\ &T_{j(\text{init})} = 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	153	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V};$ $V_{GS} = 10 \text{ V};$ see <u>Figure 13;</u> see <u>Figure 14</u>	-	16.2	-	nC

SOT428 (DPAK)

Table 1. Quick reference data ...continued

[1] Continuous current is limited by package.

2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

3. Ordering information

Table 3. Orderin	g information		
Type number	Package		
	Name	Description	Version
BUK625R2-30C	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _i ≥ 25 °C; T _i ≤ 175 °C		-	30	V
V _{GS}	gate-source voltage	Pulsed	<u>[1]</u>	-20	20	V
		DC	[2]	-16	16	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{10000000000000000000000000000000000$	<u>[3]</u>	-	90	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	81	А
I _{DM}	peak drain current	T _{mb} = 25 °C; pulsed; t _p ≤ 10 μs; see <u>Figure 3</u>		-	455	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	128	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dra	ain diode					
ls	source current	T _{mb} = 25 °C	[3]	-	90	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$		-	455	А
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 90 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	153	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		<u>[4][5][6]</u>	-	-	mJ

[1] Accumulated pulse duration not to exceed 5 mins.

[2] -16V accumulated duration not to exceed 168 hrs

[3] Continuous current is limited by package.

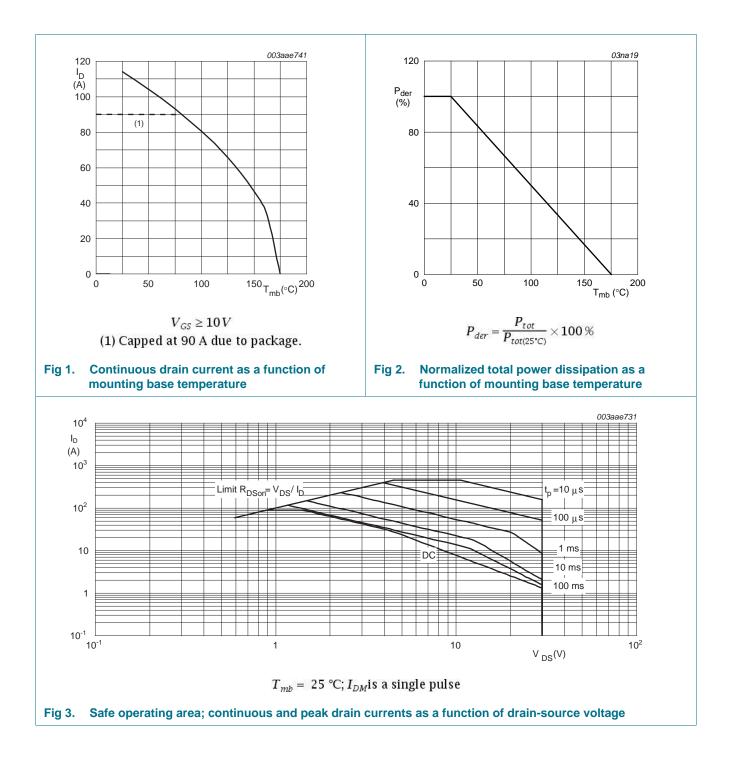
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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5. Thermal characteristics

ymbol	Parameter			Conditions	Min	Тур	Мах	Unit
th(j-mb)	thermal resistance	from junction to moun	ting base	see Figure 4	-	-	1.17	K/W
10							003aae742	
10 Zth(j-mb) (K/W)								
1	δ = 0.5							
10 ⁻¹	0.1 0.1 0.05 0.02							
10 ⁻²	single shot				P	Π	$\delta = \frac{t_p}{T}$	
10 ⁻³ 10	- ⁶ 10 ⁻⁵	10 ⁻⁴	10 ⁻³	10 ⁻²	10 ⁻¹	→ t _p + T - T - T - T - T - T - T - T - T - T	t 1	

Table 5. Thermal characteristics

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6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	30	-	-	V
	voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 9</u>	-	-	3.3	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 9</u>	0.8	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	500	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.02	1	μA
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
		V_{GS} = -20 V; V_{DS} = 0 V; T_j = 25 °C	-	2	100	nA
Doon	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u>	-	4.4	5.2	mΩ
		V _{GS} = 5 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u>	-	6	7.5	mΩ
		V _{GS} = 4.5 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u>	-	7.1	9.5	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 175 °C; see <u>Figure 12</u>	-	-	10	mΩ
Dynamic	characteristics					
Q _{G(tot)} total gate charg	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	54.8	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	31	-	nC
Q_{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 24 \text{ V}; V_{GS} = 10 \text{ V};$	-	10.2	-	nC
Q _{GD}	gate-drain charge	see <u>Figure 13;</u> see <u>Figure 14</u>	-	16.2	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	2600	3470	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	484	581	pF
C _{rss}	reverse transfer capacitance		-	288	395	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 25 \text{ V}; \text{ R}_{L} = 1 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	15.3	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	41	-	ns
t _{d(off)}	turn-off delay time		-	97	-	ns
t _f	fall time		-	66	-	ns
L _D	internal drain inductance	from upper edge of drain mounting base to centre of die ; $T_j = 25 \text{ °C}$	-	3.5	-	nH
L _S	internal source inductance	from source lead to source bond pad ; T _j = 25 °C	-	7.5	-	nH

Symbol

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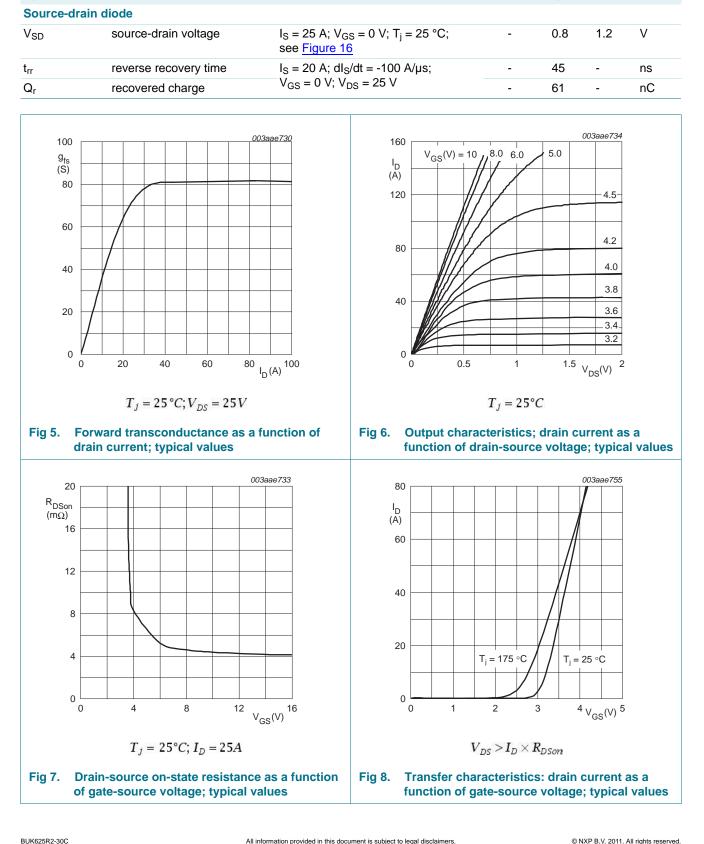
Max

Unit

Тур

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Min



Conditions

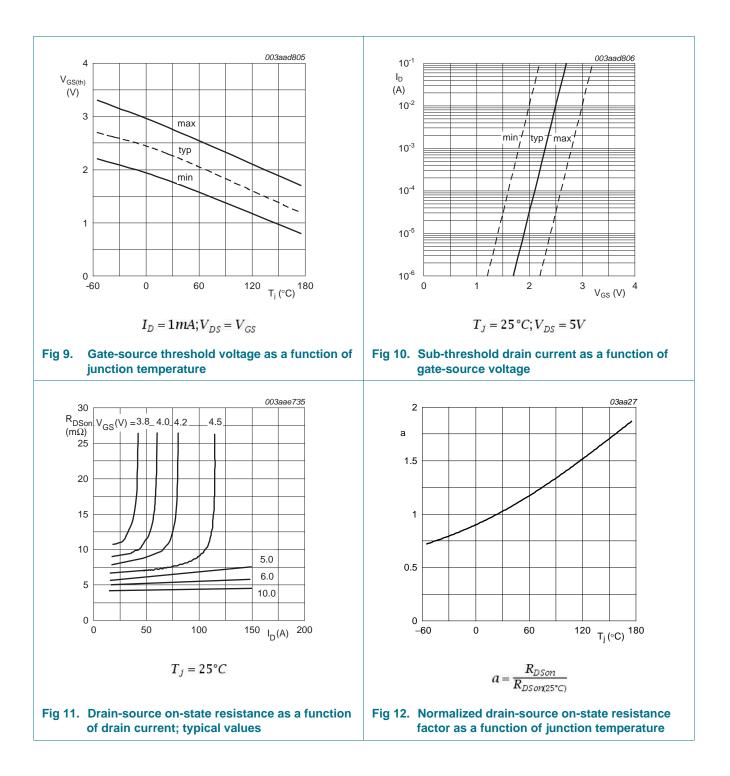
Characteristics ... continued Table 6.

Parameter

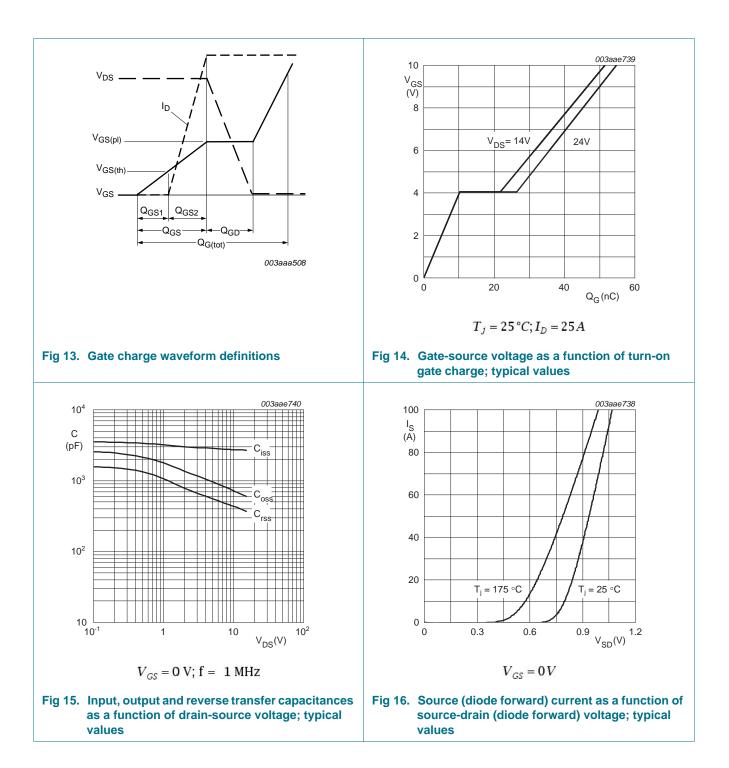
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7. Package outline

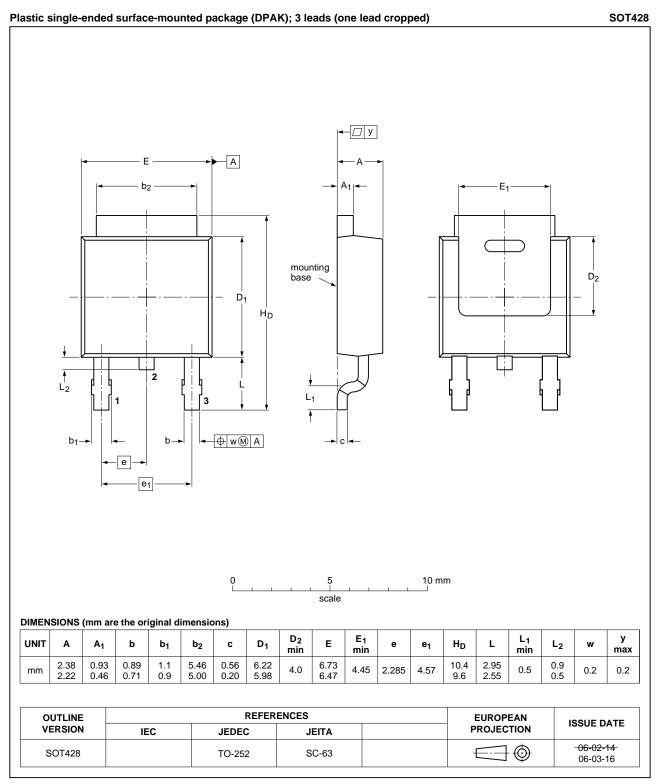


Fig 17. Package outline SOT428 (DPAK)

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8. Revision history

Table 7. Revision h	e 7. Revision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
BUK625R2-30C v.1	20110712	Product data sheet	-	-		

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9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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